

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination CHOU ET AL.	
	Examiner Evan Pert	Art Unit 2829	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,581,510	12-1996	Furusho et al.	365/201
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mori et al., "Reliability Study of Thin Inter-poly Dielectrics for Non-volatile Memory Application", 1990 IEEE, Reliability Physics Symposium, 28 th Annual Proceedings., International, pp. 132-144.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign